

Introduction

This errata sheet describes all the functional and electrical problems known in the cut 3.2 of the SPC56EL60x devices, identified with the JTAG_ID = 0x3AEA_3041.

All the topics covered in this document refer to RM0032 and SPC56EL60L3, SPC56EL60L5 datasheet (see [Section Appendix A: Additional information](#))

Device identification: Rev 2

- JTAG_ID = 0x3AEA_3041
- MCU ID Register 1 (MIDR1):
 - MAJOR_MASK[3:1]: 0x1
 - MINOR_MASK[3:1]: 0x3

This errata sheet applies to SPC56EL60 device in accordance with [Table 1](#).

Table 1. Device summary

Part number	Package
SPC56EL60L3	LQFP100
SPC56EL60L5	LQFP144

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1 Functional problems

1.1 ERR003320: Flash: single bit correction status is not available in the Error Correction Status Module (ECSM) and in the Fault Collection and Control Unit (FCCU).

Description: A single bit error correction by the Flash is not passed to the Error Correction Status Module (ECSM) and to the Fault Collection and Control Unit (FCCU). The single bit error correction is only flagged by the SBC bit of the Flash Module Configuration Register (MCR).

Workaround: Poll the SBC bit (Single Bit Correction Status) of the Flash Module Configuration Register (MCR) to detect a single bit error correction event.

1.2 ERR003697:e200z: Exceptions generated on speculative prefetch

Description: The e200z4 core can prefetch up to 2 cache lines (64 bytes total) beyond the current instruction execution point. If a bus error occurs when reading any of these prefetch locations, the machine check exception will be taken. For example, executing code within the last 64 bytes of a memory region such as internal SRAM or FLASH, may cause a bus error when the core prefetches past the end of memory. An ECC exception can occur if the core prefetches locations that are valid, but not yet initialized for ECC.

Workaround: Do not place code to be executed within the last 64 bytes of a memory region. When executing code from internal ECC SRAM, initialize memory beyond the end of the code until the next 32-byte aligned address and then an additional 64 bytes to ensure that prefetches cannot land in uninitialized SRAM.

1.3 ERR004016: ADC: Presampling on channels 9, 10, 15 leads to incorrect results

Description: On ADC channels 9 (for factory test only) , 10 (VREG_1.2V), 15 (TSENS) when performing presampling using VSS_HV_ADR (PREVAL0=01) and bypassing the sampling (PRECONV=1) results in an incorrect converted presampled value.

Workaround: ADC Conversion Timing Register 1 (CTR1) and Presampling Control Register (PSCR), field PREVAL1(bits 27:28) can be programmed to select the conversion durations and reference voltages for ADC channels 9, 10, 15.

1.4 ERR004166: CTU: FIFO full and concurrent push and pop operations

Description: With a full FIFO, if concurrent FIFO read and write operations occur, then the order of the FIFO is not correct. For example, FIFO is full and contains data A,B,C,D. Then there are POP and a PUSH requests in the same clock cycle. After the PUSH and POP operations instead of correct data B,C,D,E, the FIFO contains the data B,C,E,D. Data A is pushed out correctly, but data E and D are swapped. Application software can detect the swap between E and D by reading the CTU.FLx.ADC and CTU.FLx.N_CH fields, unless E and D refer to the same ADC and same channel.

Workaround: To reduce the risk of this issue 2 suggestions are given:

1. lower the FIFO threshold to less than the size of the FIFO (probability is reduced, but can't be fully excluded)
2. forbid 2 consecutive conversions from the same ADC and channel source to allow swap detection by reading the CTU.FLx.ADC and CTU.FLx.N_CH fields.

1.5 ERR004168: ADC: "Abort switch" aborts the ongoing injected channel as well as the upcoming normal channel

Description: If an Injected chain (jch1,jch2,jch3) is injected over a Normal chain (nch1,nch2,nch3,nch4) the Abort switch does not behave as expected.

Expected behavior:

- Correct Case (without SW Abort on jch3): Nch1-> Nch2(aborted)->Jch1 -> Jch2 -> Jch3->Nch2(restored) -> Nch3->Nch4

- Correct Case(with SW Abort on jch3): Nch1-> Nch2(aborted)->Jch1 -> Jch2 -> Jch3(aborted) ->Nch2(restored) -> Nch3->Nch4

Observed unexpected behavior:

- Fault1 (without SW abort on jch3): Nch1-> Nch2(aborted) -> Jch1 -> Jch2 -> Jch3 -> Nch3 -> Nch4(Nch2 not restored)

- Fault2 (with SW abort on jch3): Nch1-> Nch2 (aborted)->Jch1 -> Jch2 -> Jch3(aborted) -> Nch4(Nch2 not restored &Nch3 conversion skipped)

Workaround: It is possible to detect the unexpected behavior by using the CEOCFRx register. The CEOCFRx fields will not be set for a not restored or skipped channel, which indicates this issue has occurred. The CEOCFRx fields need to be checked before the next Normal chain execution (in scan mode). The CEOCFRx fields should be read by every ECH interrupt at the end of every chain execution.

1.6 ERR004186: ADC: triggering an ABORT or ABORTCHAIN before the conversion starts

Description: When ABORTCHAIN is programmed and an injected chain conversion is programmed afterward, the injected chain is aborted, but neither JECH is set, nor ABORTCHAIN is reset. In case a CTU conversion is demanded, the CTU conversion is aborted by the ADC digital logic but the CTU awaits ADC analogue acknowledgement that never arrives, stopping all CTU operation until next reset. When ABORT is programmed and normal/injected chain conversion comes afterwards, the ABORT bit is reset and chain conversion runs without a channel abort. If ABORT, or ABORTCHAIN, feature is programmed after the start of the chain conversion, it works properly.

Workaround: Do not program ABORT/ABORTCHAIN before starting the execution of the chain conversion. If the CTU is being used in trigger mode, there will always be a small vulnerable window preventing reliably reading the ADC status and using ADC.MCR[ABORT] or ADC.MCR[ABORTCHAIN]. If these functions are required, disable all CTU triggers to that ADC first and do not start the CTU if the ABORT or ABORTCHAIN flags have been set whilst the ADC was IDLE. If the CTU cannot be disabled, an optimised ABORT should be implemented in software that de-configures further channel conversions using the ADC.NMCRx registers before waiting for ADC.MSR[NSTART] == 0. At this point, the ADC should be IDLE and the NMCRx registers can be reinstated for next use.

1.7 ERR004334: MC_RGM: Device stays in reset state on external reset assertion.

Description: On an external reset that is configured to be 'long' the device may remain in reset if the system clock is configured to be sourced by a clock source other than the 16 MHz Internal RC Oscillator (IRCOSC). Recovery from the reset in this case can only be achieved via a power-down and power-up cycle. The failure condition can only be seen with the following Reset Generation Module (MC_RGM) settings for Functional Event Short Sequence register, External Reset field (RGM_FESS[SS_EXR]) and Functional Bidirectional Reset Enable register, External Reset field (RGM_FBRE[BE_EXR]):

- RGM_FESS[SS_EXR] = 0b0 (long external reset)
- RGM_FBRE[BE_EXR] = 0b0 (asserted on external reset event)

Note1: This condition can only occur if the cause of the device reset was the external reset assertion. It does not occur if, for example, the device reset was due to a power-on.

Note 2: RGM_FESS[SS_EXR] = 0b0 and RGM_FBRE[BE_EXR] = 0b0 are the default settings out of power-on reset (POR).

Workaround: There are two possible workarounds. In both, the workaround takes effect only after software has reconfigured the MC_RGM. Therefore, in order to ensure that the issue cannot occur after POR exit and before the software has executed the workaround, the system clock must not be re-configured in the Mode Entry module (MC_ME) to be sourced by a clock source other than the IRCOSC until after the workaround has been executed.

1. Workaround #1:

Always configure the external reset event to prevent the external reset output to be driven by the MC_RGM by writing 0b1 to RGM_FBRE[BE_EXR].

If the external reset has been configured to be long (RGM_FESS[SS_EXR] = 0b0) and self testing has been enabled via the flash option, the external reset pin will still be asserted from the time of external assertion until reset sequence exit after start-up self test execution.

If the external reset has been configured to be long (RGM_FESS[SS_EXR] = 0b0) and self testing has been disabled via the flash option, the external reset pin will still be asserted from the time of external assertion until the chip configuration is loaded from the flash during reset PHASE3.

If the external reset has been configured to be short (RGM_FESS[SS_EXR] = 0b1), the external reset pin will still be released as soon as it is no longer asserted from off-chip.

2. Workaround #2:

Always configure the external reset as 'short' by writing 0b1 to RGM_FESS[SS_EXR]. In addition, use software to trigger a long 'functional' or 'destructive' reset via the Mode Entry module (MC_ME) if flash initialization or start-up self test is required.

The impact of this workaround is the additional time that the device is in reset (due to the short reset sequence triggered by the external reset) and the overhead required for software to check the reset status and request a software reset.

1.8 ERR004340: LINFlexD: Buffer overrun can not be detected in UART Rx FIFO mode

Description: When the LINFlexD is configured in UART Receive (Rx) FIFO mode, the Buffer Overrun Flag (BOF) bit of the UART Mode Status Register (UARTSR) register is cleared in the subsequent clock cycle after being asserted.

User software can not poll the BOF to detect an overflow.

The LINFlexD Error Combined Interrupt can still be triggered by the buffer overrun. This interrupt is enabled by setting the Buffer Overrun Error Interrupt Enable (BOIE) bit in the LIN Interrupt enable register (LINIER). However, the BOF bit will be cleared when the interrupt routine is entered, preventing the user from identifying the source of error.

Workaround: Buffer overrun errors in UART FIFO mode can be detected by enabling only the Buffer Overrun Interrupt Enable (BOIE) in the LIN interrupt enable register (LINIER).

1.9 **ERR006726: NPC: MCKO clock may be gated one clock period early when MCKO frequency is programmed as SYS_CLK/8.and gating is enabled**

Description: The Nexus auxiliary message clock (MCKO) may be gated one clock period early when the MCKO frequency is programmed as SYS_CLK/8 in the Nexus Port Controller Port Configuration Register (NPC_PCR[MCKO_DIV]=111) and the MCKO gating function is enabled (NPC_PCR[MCKO_GT]=1). In this case, the last MCKO received by the tool prior to the gating will correspond to the END_MESSAGE state. The tool will not receive an MCKO to indicate the transition to the IDLE state, even though the NPC will transition to the IDLE state internally. Upon re-enabling of MCKO, the first MCKO edge will drive the Message Start/End Output (MSEO=11) and move the tool's state to IDLE.

Workaround: Expect to receive the MCKO edge corresponding to the IDLE state upon re-enabling of MCKO after MCKO has been gated.

1.10 **ERR006967: eDMA: Possible misbehavior of a preempted channel when using continuous link mode**

Description: When using Direct Memory Access (DMA) continuous link mode Control Register Continuous Link Mode (DMA_CR[CLM]) = 1) with a high priority channel linking to itself, if the high priority channel preempts a lower priority channel on the cycle before its last read/write sequence, the counters for the preempted channel (the lower priority channel) are corrupted. When the preempted channel is restored, it continues to transfer data past its "done" point (that is the byte transfer counter wraps past zero and it transfers more data than indicated by the byte transfer count (NBYTES)) instead of performing a single read/write sequence and retiring. The preempting channel (the higher priority channel) will execute as expected.

Workaround: Disable continuous link mode (DMA_CR[CLM]=0) if a high priority channel is using minor loop channel linking to itself and preemption is enabled. The second activation of the preempting channel will experience the normal startup latency (one read/write sequence + startup) instead of the shortened latency (startup only) provided by continuous link mode.

1.11 **ERR007120: NZxC3: DQTAG implemented as variable length field in DQM message**

Description: The e200zx core implements the Data Tag (DQTAG) field of the Nexus Data Acquisition Message (DQM) as a variable length packet instead of an 8-bit fixed length packet. This may result in an extra clock ("beat") in the DQM trace message depending on the Nexus port width selected for the device.

Workaround: Tools should decode the DQTAG field as a variable length packet instead of a fixed length packet.

1.12 ERR007274: LINFlexD: Consecutive headers received by LIN Slave triggers error interrupt

Description: As per the Local Interconnect Network (LIN) specification, the processing of one frame should be aborted by the detection of a new header sequence. In LINFlexD, if the LIN Slave receives a new header instead of data response corresponding to a previous header received, it triggers a framing error during the new header's reception. The LIN Slave still waiting for the data response corresponding to the first header received.

The following three steps should be followed -

1. Set the MODE bit in the LIN Time-Out Control Status Register (LINTCSR[MODE]) to '0'.
2. Set Idle on Timeout in the LINTCSR[IOT] register to '1'.
3. Configure master to wait until the occurrence of the Output Compare flag in LIN Error Status Register (LINESR[OCF]) before sending the next header. This flag causes the LIN Slave to go to an IDLE state before the next header arrives, which will be accepted without any framing error.

1.13 ERR007322: FlexCAN: Bus Off Interrupt bit is erroneously asserted when soft reset is performed while

Description: Under normal operation, when FlexCAN enters in Bus Off state, a Bus Off Interrupt is issued to the CPU if the Bus Off Mask bit (CTRL[BOFF_MSK]) in the Control Register is set. In consequence, the CPU services the interrupt and clears the ESR[BOFF_INT] flag in the Error and Status Register to turn off the Bus Off Interrupt. In continuation, if the CPU performs a soft reset after servicing the bus off interrupt request, by either requesting a global soft reset or by asserting the MCR[SOFT_RST] bit in the Module Configuration Register, once MCR[SOFT_RST] bit transitions from 1 to 0 to acknowledge the soft reset completion, the ESR[BOFF_INT] flag (and therefore the Bus Off Interrupt) is re-asserted.

The defect under consideration is the erroneous value of Bus Off flag after soft reset under the scenario described in the previous paragraph.

The Fault Confinement State (ESR[FLT_CONF] bit field in the Error and Status Register) changes from 0b11 to 0b00 by the soft reset, but gets back to 0b11 again for a short period, resuming after certain time to the expected Error Active state (0b00). However, this late correct state does not reflect the correct ESR[BOFF_INT] flag which stays in a wrong value and in consequence may trigger a new interrupt service.

Workaround: To prevent the occurrence of the erroneous Bus Off flag (and eventual Bus Off Interrupt) the following soft reset procedure must be used:

1. Clear CTRL[BOFF_MSK] bit in the Control Register (optional step in case the Bus Off Interrupt is enabled).
2. Set MCR[SOFT_RST] bit in the Module Configuration Register.
3. Poll MCR[SOFT_RST] bit in the Module Configuration Register until this bit is cleared.
4. Wait for 4 peripheral clocks.
5. Poll ESR[FLTCONF] bit in the Error and Status Register until this field is equal to 0b00.
6. Write "1" to clear the ESR[BOFF_INT] bit in the Error and Status Register.
7. Set CTRL[BOFF_MSK] bit in the Control Register (optional step in case the Bus Off Interrupt is enabled).

1.14 ERR007352: DSPI: reserved bits in slave CTAR are writable

Description: When the Deserial/Serial Peripheral Interface (DSPI) module is operating in slave mode (the Master [MSTR] bit of the DSPI Module Configuration Register [DSPIx_MCR] is cleared), bits 10 to 31 (31 = least significant bit) of the Clock and Transfer Attributes Registers (DSPIx_CTARx) should be read only (and always read 0). However, these bits are writable, but setting any of these bits to a 1 does not change the operation of the module.

Workaround: There are two possible workarounds.
 Workaround 1: Always write zeros to the reserved bits of the DSPIx_CTARn_SLAVE (when operating in slave mode).
 Workaround 2: Mask the reserved bits of DSPIx_CTARn_SLAVE when reading the register in slave mode.

1.15 ERR007394: MC_ME: Incorrect mode may be entered on low-power mode exit

Description: For the case when the Mode Entry (MC_ME) module is transitioning from a run mode (RUN0/1/2/3) to a low power mode (HALT/STOP/STANDBY*) if a wake-up or interrupt is detected one clock cycle after the second write to the Mode Control (ME_MCTL) register, the MC_ME will exit to the mode previous to the run mode that initiated the low power mode transition.
 Example correct operation DRUN->RUN1-> RUN3->STOP->RUN3
 Example failing operation DRUN->RUN1-> RUN3->STOP->RUN1|

Note: STANDBY mode is not available on all MPC56xx microcontrollers

Workaround: To ensure the application software returns to the run mode (RUN0/1/2/3) prior to the low power mode (HALT/STOP/STANDBY*) it is required that the RUNx mode prior to the low power mode is entered twice.
 The following example code shows RUN3 mode entry prior to a low power mode transition.

```
ME.MCTL.R = 0x70005AF0; /* Enter RUN3 Mode & Key */
ME.MCTL.R = 0x7000A50F; /* Enter RUN3 Mode & Inverted Key */
while (ME.GS.B.S_MTRANS) {} /* Wait for RUN3 mode transition to complete */
ME.MCTL.R = 0x70005AF0; /* Enter RUN3 Mode & Key */
ME.MCTL.R = 0x7000A50F; /* Enter RUN3 Mode & Inverted Key */
```

```
while (ME.GS.B.S_MTRANS) {} /* Wait for RUN3 mode transition to complete */  
/* Now that run mode has been entered twice can enter low power mode */  
/* (HALT/STOP/STANDBY*) when desired. */
```

1.16 ERR007877: FlexPWM: do not enable the fault filter

Description: Operation of the fault pin filter of the Flexible Pulse Width Modulation (FLEX_PWM) may be inconsistent if the Fault Filter is enabled, by setting the Filter Period greater than zero in the Fault Filter register (FFILT[FILT_PER] > 0). The fault filter flag may be set even though the pulse is shorter than the filter time.

Workaround: Do not enable the PWM fault pin filters. Disable the fault pin filters by setting the Fault Filter Period to 0 in the Fault Filter Register (FFILT[FILT_PER] = 0).

1.17 ERR008070: SWG: GPIO[55] functionality is not available unless the SWG is powered down

Description: The General Purpose Input/Output 55 (GPIO[55]) functionality on port D[7] is disabled if the Sine Wave Generator module (SWG) is not in power down mode. The SWG will not enter power down mode if the SWG clock input is disabled.

Workaround: Ensure that the SWG clock input is enabled via the Aux Clock 0 Divider Configuration 1 register (CGM_AC0_DC1[DE1]=1) prior to putting the SWG in power down mode in the SWG control register (SWG_CTRL[PDS] = 1). This will allow GPIO[55] functionality on port D[7].

Appendix A Additional information

A.1 Reference document

- SPC56EL60 32-bit MCU family built on the embedded Power Architecture® (RM0032, Doc ID 15265).
- 32-bit Power Architecture® microcontroller for automotive SIL3/ASILD chassis and safety applications (SPC56EL60L3, SPC56EL60L5 datasheet, Doc ID 15457).

A.2 Acronyms

Table 2. Acronyms

Acronym	Name
ADC	Analog-to-digital converter
APC	Analog pad control
BAM	Boot assist module
CMU	Clock monitor unit
CPU	Control processing unit
CHIERFR	Controller host interface error flag register
CTU	Cross trigger unit
DMA	Direct memory access
DPM	Decoupled parallel mode
ECSM	Error correction status module
FCCU	Fault collection and control unit
FIFO	First in first out
ILSA_EF	Illegal system bus address error flag
LSM	Lock step mode
MB	Message buffer
MCU	Microcontroller unit
PCR	Pad configuration register
POC	Protocol operation control
RCCU	Redundancy control checker unit
RWE	Read-while-write event error
RWW	Read while write
RXGMASK	RX global mask
RXIMR	RX individual mask register
SBC	Single bit correction-status
SLL	Secondary low/mid address space block lock register

Table 2. Acronyms (continued)

Acronym	Name
SWG	Sine-wave generator
XOSC	External oscillator

Revision history

Table 3. Document revision history

Date	Revision	Changes
08-Jul-2014	1	Initial release.
07-Oct-2014	2	Add the following errata: - ERR007877 - ERR008070.

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